SQUID Multiplexer Update

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Outline

Time Domain Multiplexers

- TDM overview and scaling
- 4 × 32 test setup 256 pixels arrays
- SCUBA wafermux (40 × 32) results
- Next-generation TDM

Microwave Reflectometry for Multiplexing

- Overview
- High-Q resonators
- Conclusions



SQUID Time Domain MUX Overview



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Some constraints from the TES, the SQUIDS, and the system

$$\begin{array}{l} \text{= System timing: } t_{\text{frame}} = N_{\text{mux}}(t_{\text{settling}} + t_{\text{readout}}) \\ \text{= Closed loop bandwidth: } f_{\text{closed loop}} = \frac{1}{2t_{\text{frame}}} \\ \text{= Switching transients : } t_{\text{settling}} \geq \frac{1}{f_{\text{fopen loop BW}}} \implies f_{\text{closed loop BW}} = \frac{f_{\text{open loop BW}}}{N_{\text{mux}}} \\ \text{= Aliasing of Amplifier Noise : } I_{N(\text{tes})} = \frac{\Phi_N \sqrt{\pi N_{\text{mux}}}}{M_{\text{in}}} \\ \text{= SQUID Nonlinearity: } \Delta \Phi_{\text{max}} = \frac{I_0 N_{\text{mux}} M_{\text{in}}}{\tau_{\pm} f_{\text{open loop BW}}} \end{array}$$

Apply these constraints to engineer multiplexing solution for desired N_{mux} with allowable degradation





Detector	$ au_+$	Detector	MUX'ed	Open-loop	N _{mux}
type	$ au_{-}$	resolution	resolution	bandwidth	per column
8-channel	46 \pm 114 ι μ s	3.20 eV	$3.74\pm0.12~\mathrm{eV}$	I.5 MHz	8
l 6-channel	62 \pm 114 ι μ s	4.15 eV	$4.74\pm$ 0.16 eV	1.5 MHz	16



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γ -ray ¹	0.60 / 1.9 ms	4125	4125	2.0 MHz	8

¹See Joel Ullom's upcoming talk - resolution is quoted as $E/\delta E$



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16-channel	62 \pm 114 ι μ s	4.15 eV	$4.74\pm$ 0.16 eV	1.5 MHz	16
γ -ray ¹	0.60 / 1.9 ms	4125	4125	2.0 MHz	8
γ -ray	1.2 / 1.9 ms	4125	3700	2.0 MHz	32
32-channel	0.42 / 1.7 ms	2.45 eV	2.57 eV	2.0 MHz	32

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"Next" ²	l ms	3.6 eV	4.0 eV	3.5 MHz	196
"Con-X" ²	300 μ s	1.8 eV	2.0 eV	12 MHz	95
"Xeus" ²	50 μ s	4.5 eV	5.0 eV	12 MHz	32

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²Assumes critical damping



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4×32 Infrastructure



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4×32 Infrastructure - 256 pixel detector



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4×32 Infrastructure - collimated detector



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SCUBA-2 Multiplexers





SCUBA-2

- Wafer-scale processing
- Separate Mux and TES wafers
- Imager assembled with indium bump-bonding
- 40 × 32 pixel sub-mm imager
- Camera consists of 8 imagers (4 at 450 μm 4 at 850 μm)



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- Strong central peak with outliers
- Mean = 190 µA

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- I high I_c row parasitic short
- 2.5 bad lines
- ~20 bad pixels







- Much broader not well distributed
- Can we use this?



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- 3.5 bad lines
- ~20 bad pixels
- Strong gradient across the wafer
- Can compensate by adjusting row-select and second-stage fb values. Algorithm works for a wide variety of low spatial frequency surfaces.





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- Second-order gradiometric design (less shielding required)
- Improved resistance to flux trapping





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- Improved resistance to flux trapping
- Improved dynamic range (4× improvement in N_{mux})
- Low noise
 (~ 2× improvement at 4K)





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- Use microwave reflectometry to implement FDM multiplexer
- Large channel counts possible
- Proof of principle demonstrated using DC SQUIDS (Irwin APL 2004)
- Demonstration experiment for high-Q thin film resonators





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Microwave test resonators



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- Resonators perform with predicted center frequencies
- Obtain $Q \sim 100,000$
- Q limited by loss tangent in ECR SiO₂
- Substrate is UHP (> 17 KΩ-cm undoped) Si



- Time domain multiplexers have been demonstrated to work as predicted with a variety of x-ray and γ-ray detectors
- Soon demonstrate 128 pixels on a 256 pixel detector
- Wafer-scale SCUBA-2 multiplexers show good parameter uniformity
- Next generation multiplexers will improve performance and improve operational simplicity
- \blacksquare Resonant test structures for microwave multiplexers have been demonstrated with $Q\sim$ 100,000

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Outline

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2 TDM

- Mux constraints
- LTD-11 results
- Examples
- 4 x 32 infrastructure
- SCUBA-2
- Next generation TDM

3 Microwave mux

- Resonator chip
- Resonator results